

**April 2007** 

## FDD8444L

# N-Channel PowerTrench® MOSFET

40V, 50A, 6.0m $\Omega$ 

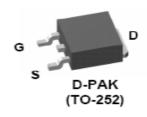
#### **Features**

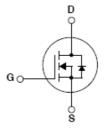
- Typ  $r_{DS(on)}$  = 3.8m $\Omega$  at  $V_{GS}$  = 5V,  $I_D$  = 50A
- Typ  $Q_{g(tot)}$  = 46nC at  $V_{GS}$  = 5V
- Low Miller Charge
- Low Q<sub>rr</sub> Body Diode
- UIS Capability (Single Pulse/ Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant



### **Applications**

- Automotive Engine Control
- Powertrain Management
- Solenoid and Motor Drivers
- Electronic Transmission
- Distributed Power Architecture and VRMs
- Primary Switch for 12V and 24V systems





# **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		Ratings	Units
$V_{DSS}$	Drain to Source Voltage		40	V
V <sub>GS</sub>	Gate to Source Voltage		±20	V
	Drain Current Continuous (T <sub>C</sub> < 150°C, V <sub>GS</sub> = 10V)	(Note 1)	50	
$I_D$	Continuous ( $T_{amb} = 25^{\circ}C$ , $V_{GS} = 10V$ , with $R_{\theta JA} = 52^{\circ}C/W$ )		16	Α
	Pulsed		See Figure 4	
E <sub>AS</sub>	Single Pulse Avalanche Energy	(Note 2)	295	mJ
ר	Power Dissipation		153	W
$P_{D}$	Derate above 25°C		1.02	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature		-55 to +175	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.98	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252, 1in <sup>2</sup> copper pad area	52	°C/W

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8444L	FDD8444L	TO-252AA	13"	12mm	2500 units

# Electrical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

Symbol	Parameter	1	Test Conditions	Min	Тур	Max	Units	
Off Oh								
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# Off Characteristics

B <sub>VDSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0$	V	40	1	-	٧
1	Zero Gate Voltage Drain Current	$V_{DS} = 32V$ ,		-	1	1	^
IDSS	Zero Gate Voltage Drain Guirent	$V_{GS} = 0V$	$T_{\rm J} = 150^{\rm o}{\rm C}$	-	-	250	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA

#### **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1	1.8	3	V
	$I_D = 50A, V_{GS} = 10V$	-	3.5	5.2		
		$I_D = 50A, V_{GS} = 5V$	-	3.8	6.0	
r <sub>DS(on)</sub>	Drain to Source On Resistance	$I_D = 50A, V_{GS} = 4.5V$	-	4.0	6.5	mΩ
		I <sub>D</sub> = 50A, V <sub>GS</sub> = 5V, T <sub>J</sub> = 175°C	-	6.8	10.7	

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V	N. /	-	5530	-	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = ( f = 1MHz	JV,	-	605	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/12		-	400	-	pF
$R_G$	Gate Resistance	f = 1MHz		-	1.7	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 5V	$V_{GS} = 0$ to 5V		-	46	60	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0$ to 2V	V <sub>DD</sub> = 20V	-	5.4	7	nC
$Q_{gs}$	Gate to Source Gate Charge		$I_{D} = 50A$	-	16.3	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau		$I_g = 1.0 mA$	-	10.9	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge			-	21	-	nC

### Electrical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
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### **Switching Characteristics**

t <sub>on</sub>	Turn-On Time		-	-	104	ns
t <sub>d(on)</sub>	Turn-On Delay Time	.,	-	18.7	-	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 20V, I_{D} = 50A$ $V_{GS} = 5V, R_{GS} = 2\Omega$	-	46	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> – 5V, K <sub>GS</sub> – 212	-	42	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	19.2	-	ns
t <sub>off</sub>	Turn-Off Time		-	-	96	ns

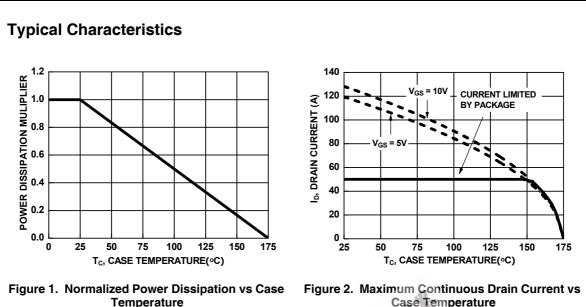
#### **Drain-Source Diode Characteristics**

V <sub>SD</sub> Source to Drain Diode Voltage	I <sub>SD</sub> = 50A	-	0.9	1.25	V	
$V_{SD}$	Source to Drain Diode Voltage	I <sub>SD</sub> = 25A	-	0.8	1.0	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 50A, dI <sub>E</sub> /dt = 100A/μs	-	34	44	ns
Q <sub>rr</sub>	Reverse Recovery Charge	i <sub>F</sub> = 50A, di <sub>F</sub> /dt = 100A/μs	-	29	38	nC

Package current limitation is 50A.
 Starting T<sub>J</sub> = 25°C, L = 0.37mH, I<sub>AS</sub> = 40A.



This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/ All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.



**Temperature** 

**Case Temperature** 

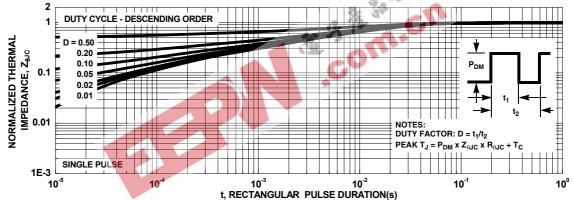


Figure 3. Normalized Maximum Transient Thermal Impedance

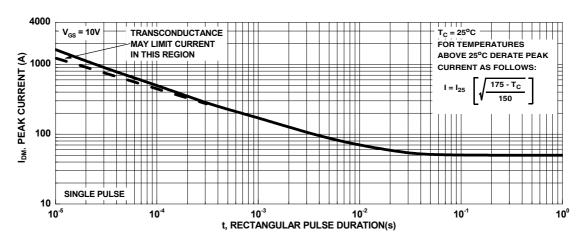
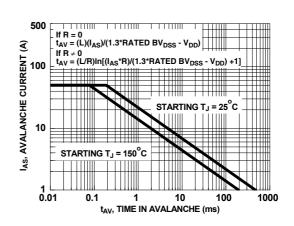


Figure 4. Peak Current Capability

#### **Typical Characteristics** 1000 10us ID, DRAIN CURRENT (A) 100 10 1ms OPERATION IN THIS SINGLE PULSE AREA MAY BE LIMITED BY rDS(on) T.I = MAX RATED 10<sub>ms</sub> T<sub>C</sub> = 25<sup>O</sup>C DC 0.1 10 100 V<sub>DS</sub>, DRAIN TO SOURCE VOLTAGE (V) Figure 5. Forward Bias Safe Operating Area 100 PULSE DURATION = 80µs DUTY CYCLE = 0.5% MAX 80



NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability

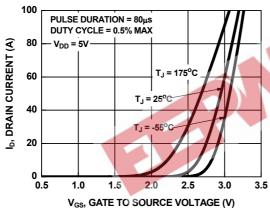


Figure 7. Transfer Characteristics

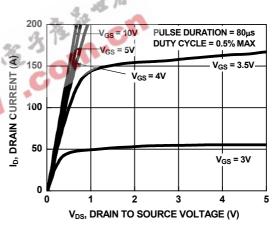


Figure 8. Saturation Characteristics

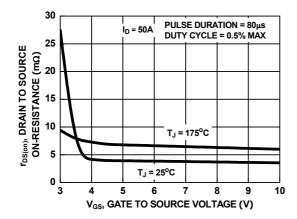


Figure 9. Drain to Source On-Resistance Variation vs Gate to Source Voltage

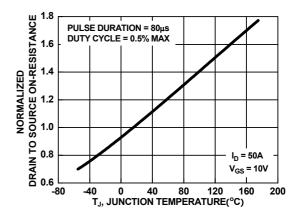
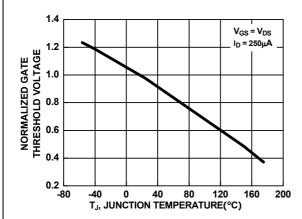


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

### **Typical Characteristics**



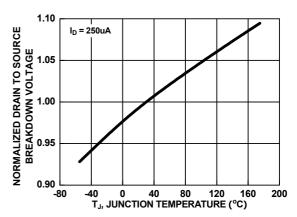
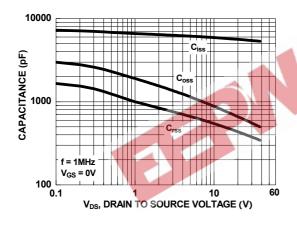


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature



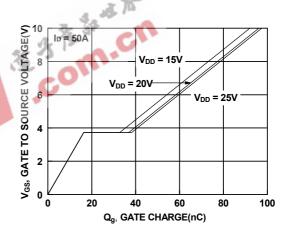


Figure 13. Capacitance vs Drain to Source Voltage

Figure 14. Gate Charge vs Gate to Source Voltage





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